## Notice of References Cited Application/Control No. 10/827,012 Examiner Henok G. Heyi Applicant(s)/Patent Under Reexamination DIERKS, DIETER Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,297,436 A	10-1981	Kubotera et al.	430/319
*	В	US-4,588,664 A	05-1986	Fielding et al.	430/1
*	С	US-5,244,774 A	09-1993	Usami et al.	430/270.14
*	D	US-5,667,953 A	09-1997	Bertoldi et al.	430/567
*	Е	US-6,066,218 A	05-2000	Kuhn et al.	156/87
*	F	US-6,205,112 B1	03-2001	Weidner, Steven Lee	369/275.3
*	G	US-6,235,461 B1	05-2001	Sismondi et al.	430/569
*	Н	US-2003/0099911 A1	05-2003	Ceruti et al.	430/621
*	1	US-6,747,930 B1	06-2004	Weldon et al.	369/53.21
*	J	US-2006/0250930 A1	11-2006	Worthington et al.	369/100
	К	US-	- A1		
	L	US-	11		
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.